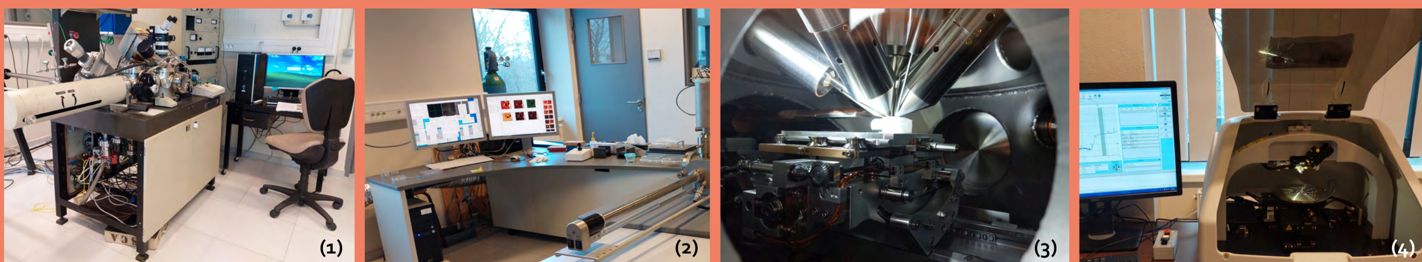
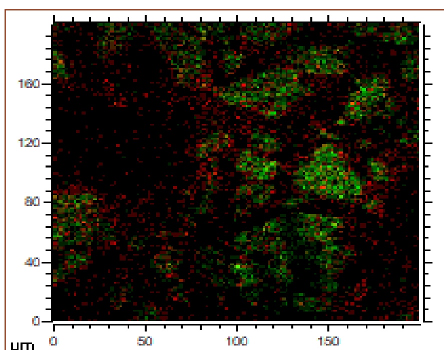


SUCH : SUrface CHaracterization

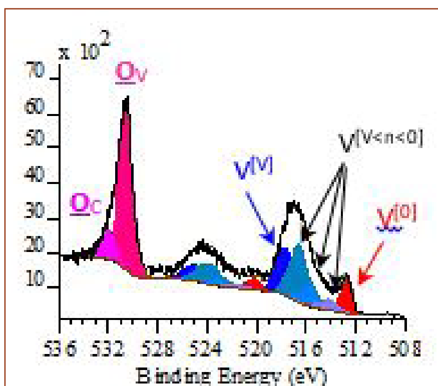
WHAT WE OFFER : services and expertise

- Characterization / tests / analysis and interpretation realized by highly qualified UCLouvain members
- Surface analysis tools (probing the first nanometers depth) in the context of material science and (bio)nanotechnology



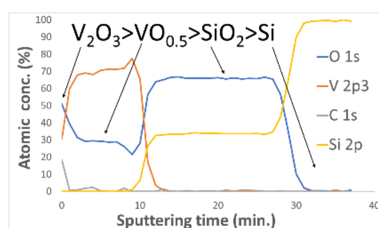
ToF-SIMS

- Solid state mass spectrometry
- 2D molecular image
- 3D depth profile



XPS

- Elemental quantification
- Chemical states
- XPS imaging and depth profile



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XPS

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(1) XPS spectrometer – (2) ToF-SIMS spectrometer – (3) Inside the ToF-SIMS spectrometer – (4) Stylus profilometer

SUCH
SUrface CHaracterization
UCLouvain

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1348 Louvain-la-Neuve
Belgium

Soutenu par
Le Brabant wallon

Avec le soutien de la Wallonie